

**ABSTRACT**

The disclosure relates to a semiconductor device testing apparatus, a semiconductor device testing system, and a semiconductor device testing method, in particular a method for measuring or trimming, respectively, the impedance of driver devices provided in a semiconductor device, wherein a device, in particular a driver device, comprising each a pull-up circuit and a pull-down circuit is used, and wherein the method includes: joint activating of both the pull-up circuit and the pull-down circuit; and determining a first current flowing through the pull-up circuit or the pull-down circuit, respectively, with jointly activated pull-up and pull-down circuits.